

Page i

DIODES, MICROWAVE, SILICON, TUNING VARACTOR, BASED ON TYPES ML4351 THRU ML4354 ESCC Detail Specification No. 5512/006

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PAGE	ii
ISSUE	1

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Pages 1 to 26

DIODES, MICROWAVE, SILICON, TUNING VARACTOR, BASED ON TYPES ML4351 THRU ML4354 ESA/SCC Detail Specification No. 5512/006



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PAGE 2

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PAGE 3

ISSUE 1

TABLE OF CONTENTS

1.1 Scope 5 1.2 Type Variants 5 1.3 Maximum Ratings 5 1.4 Parameter Derating Information 5 1.5 Physical Dimensions 5 1.6 Functional Diagram 5 1.7 Handling Precautions 5 2. APPLICABLE DOCUMENTS 5 3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1 General 15 4.2 Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.2 Deviations from Suburian and Electrical Measurements 15 4.2.3 Deviations from Suburian and Electrical Measurements 15 4.2.4 Deviations from Qualification Tests 15 4.2.5 Deviations from Una Acceptance Tests 15 4.3 Mechanical and Environmental Requirements 15 4.3 Mechanical and Environmental Requirements 16	1.	GENERAL	<u>Page</u> 5
1.2 Type Variants 5 1.3 Maximum Ratings 5 1.4 Parameter Derating Information 5 1.5 Physical Dimensions 5 1.6 Functional Diagram 5 1.7 Handling Precautions 5 2. APPLICABLE DOCUMENTS 5 3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1 General 15 4.2 Deviations from Generic Specification 15 4.2.1 Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.1 Deviations from Burn-in and Electrical Measurements 15 4.2.2 Deviations from Burn-in and Electrical Measurements 15 4.2.3 Deviations from Unit Acceptance Tests 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4.1 Case	1.1	Scope	5
1.3 Maximum Ratings 5 1.4 Parameter Derating Information 5 1.5 Physical Dimensions 5 1.6 Functional Diagram 5 1.7 Handling Precautions 5 2. APPLICABLE DOCUMENTS 5 3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1 General 15 4.2 Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.1 Deviations from Eural Production Tests 15 4.2.2 Deviations from Burn-in and Electrical Measurements 15 4.2.3 Deviations from Qualification Tests 15 4.2.4 Deviations from Unit Acceptance Tests 15 4.3 Mechanical and Environmental Requirements 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.4.2 Lead Materials and Finish 16 4.5.1	1.2	Type Variants	5
1.5 Physical Dimensions 5 1.6 Functional Diagram 5 1.7 Handling Precautions 5 2. APPLICABLE DOCUMENTS 5 3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1 General 15 4.2 Deviations from Generic Specification 15 4.2.1 Deviations from Generic Specification 15 4.2.2.1 Deviations from Burn-in and Electrical Measurements 15 4.2.2.2 Deviations from Burn-in and Electrical Measurements 15 4.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Burn-in and Electrical Measurements 15 4.2.5 Deviations from Burn-in and Electrical Measurements 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3	1.3		
1.6 Functional Diagram 5 1.7 Handling Precautions 5 2. APPLICABLE DOCUMENTS 5 3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1 General 15 4.2.1 Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.1 Deviations from Final Production 15 4.2.2 Deviations from Final Production 15 4.2.3 Deviations from Pinal Production 15 4.2.4 Deviations from Undiffication Tests 15 4.2.5 Deviations from Und Acceptance Tests 15 4.2.5 Deviations from Und Acceptance Tests 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.4.1 Case 17 <td>1.4</td> <td>Parameter Derating Information</td> <td></td>	1.4	Parameter Derating Information	
1.7 Handling Precautions 5 2. APPLICABLE DOCUMENTS 5 3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1 General 15 4.2 Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.2.1 Deviations from Burn-in and Electrical Measurements 15 4.2.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Burn-in and Electrical Measurements 15 4.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Dualification Tests 15 4.2.5 Deviations from Qualification Tests 15 4.2.1 Deviations from Lot Acceptance Tests 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.1 Dimension Check 15 4.3.2 Levil Measurements 16 4.4.2 Lead Materials and	1.5	Physical Dimensions	
2. APPLICABLE DOCUMENTS 5 3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1. General 15 4.2. Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.1 Deviations from Special In-process Controls 15 4.2.1 Deviations from Burn-in and Electrical Measurements 15 4.2.3 Deviations from Dunlification Tests 15 4.2.4 Deviations from Lot Acceptance Tests 15 4.2.5 Deviations from Lot Acceptance Tests 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.1 General 17 4.5.2 Traceability Infor	1.6	Functional Diagram	
3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS 5 4. REQUIREMENTS 15 4.1 General 15 4.2. Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.2. Deviations from Burn-in and Electrical Measurements 15 4.2.3. Deviations from Qualification Tests 15 4.2.4. Deviations from Lot Acceptance Tests 15 4.2.5. Deviations from Lot Acceptance Tests 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.2 Weight 16 4.4.1 Case 17 4.4.2 Lead Materials and Finishes 17 4.4.1 Case 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.1 Fraceability Information 18 4.6.1 Electrical Measurements at Room Temper	1.7	Handling Precautions	5
4.1 General 15 4.2 Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.2 Deviations from Final Production Tests 15 4.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Qualification Tests 15 4.2.5 Deviations from Lot Acceptance Tests 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4.1 Case 17 4.4.1 Case 17 4.4.2 Lead Materials and Finishes 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7.2	2.	APPLICABLE DOCUMENTS	5
4.1 General 15 4.2 Deviations from Generic Specification 15 4.2.1 Deviations from Special In-process Controls 15 4.2.2 Deviations from Eurn-in and Electrical Measurements 15 4.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Qualification Tests 15 4.2.5 Deviations from Qualification Tests 15 4.2.5 Deviations from Qualification Tests 15 4.2.5 Deviations from Contects 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4.1 Case 17 4.4.2 Lead Materials and Finishs 17 4.5.1 Case 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.	3.	TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS	5
4.2. Deviations from Generic Specification 15 4.2.1. Deviations from Special In-process Controls 15 4.2.2. Deviations from Final Production Tests 15 4.2.3. Deviations from Burn-in and Electrical Measurements 15 4.2.4. Deviations from Qualification Tests 15 4.2.5. Deviations from Lot Acceptance Tests 15 4.3.1. Mechanical and Environmental Requirements 15 4.3.1. Dimension Check 15 4.3.2. Weight 16 4.3.3. Terminal Strength 16 4.4.1. Case 17 4.4.2. Lead Materials and Finishes 17 4.4.1. Case 17 4.4.2. Lead Materials and Finish 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.1 Traceability Information 17 4.5.2 Traceability Information 18 4.6.1 Electrical Measurements at High and Low Temperatures 18	4.	REQUIREMENTS	15
4.2.1 Deviations from Special In-process Controls 15 4.2.2 Deviations from Finnal Production Tests 15 4.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Qualification Tests 15 4.2.5 Deviations from Lot Acceptance Tests 15 4.3.1 Dimension Check 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.6.3 Circuits for Electrical Measurements 18 4.7.1 Parameter Drift Values 18 <	4.1	General	15
4.2.2 Deviations from Final Production Tests 15 4.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Lot Acceptance Tests 15 4.2.5 Deviations from Lot Acceptance Tests 15 4.3 Mechanical and Environmental Requirements 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4.1 Case 17 4.4.1 Case 17 4.4.2 Lead Materials and Finishes 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18	4.2	Deviations from Generic Specification	15
4.2.3 Deviations from Burn-in and Electrical Measurements 15 4.2.4 Deviations from Qualification Tests 15 4.2.5 Deviations from Lot Acceptance Tests 15 4.3 Mechanical and Environmental Requirements 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5.3 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7.1 Burn-in Tests 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3	4.2.1	Deviations from Special In-process Controls	15
4.2.4 Deviations from Qualification Tests 15 4.2.5 Deviations from Lot Acceptance Tests 15 4.3 Mechanical and Environmental Requirements 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finishe 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 <td< td=""><td>4.2.2</td><td>Deviations from Final Production Tests</td><td>15</td></td<>	4.2.2	Deviations from Final Production Tests	15
4.2.5 Deviations from Lot Acceptance Tests 15 4.3 Mechanical and Environmental Requirements 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at High and Low Temperatures 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8.1	4.2.3	Deviations from Burn-in and Electrical Measurements	
4.3.1 Mechanical and Environmental Requirements 15 4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Hom Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8 Environmental and Endurance Tests </td <td></td> <td></td> <td></td>			
4.3.1 Dimension Check 15 4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8.1 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Enduran		•	
4.3.2 Weight 16 4.3.3 Terminal Strength 16 4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Gircuit for High Temperature Reverse Bias Burn-in 18 4.8.1 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.3 Conditi			
4.3.3 Terminal Strength 16 4.4 Materials and Finishes 17 4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8.1 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.3 Conditions for Operating Life Tests 23 <td< td=""><td></td><td></td><td></td></td<>			
4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.6.3 Circuits for Electrical Measurements 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8.1 Electrical Measurements on Completion of Environmental Tests 23 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.3 Conditions for Operating Life Tests 23 4.9 Total Dose Irradiation Testing 23			
4.4.1 Case 17 4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Hoom Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Measurements on Completion of Environmental Tests 23 4.8.1 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.2 Electrical Circuits for Operating Life Tests 23 4.8.4 Electrical Circuits for Operating Life Tests 23			
4.4.2 Lead Materials and Finish 17 4.5 Marking 17 4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8 Environmental and Endurance Tests 23 4.8.1 Electrical Measurements on Completion of Environmental Tests 23 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.3 Conditions for Operating Life Tests 23 4.9 Total Dose Irradiation Testing 23 4.9.1 Application 23			
4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements at Room Temperature 18 4.6.1 Electrical Measurements at High and Low Temperatures 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8 Environmental and Endurance Tests 23 4.8.1 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.2 Electrical Circuits for Operating Life Tests 23 4.8.4 Electrical Circuits for Operating Life Tests 23 4.9.1 Application 23 4.9.2 Bias Conditions 23 4.9.3 Electrical Measurements 32			
4.5.1 General 17 4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8 Environmental and Endurance Tests 23 4.8.1 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.2 Electrical Circuits for Operating Life Tests 23 4.8.4 Electrical Circuits for Operating Life Tests 23 4.8.5 Total Dose Irradiation Testing 23 4.9.1 Application 23 4.9.2 Bias Conditions 23 4.9.3 Electrical Measurements 323 4.9.3 Electrical Measurements 323 4.9.1 Electrical Measurements 323 4.9.2 Bias Conditions 523 4.9.3 Electrical Measurements 323 4.9.3 Electrical Measurements 323 4.9.1 Application 223 4.9.2 Bias Conditions 523 4.9.3 Electrical Measurements 323			
4.5.2 Cathode Identification 17 4.5.3 The SCC Component Number 17 4.5.4 Traceability Information 18 4.6 Electrical Measurements 18 4.6.1 Electrical Measurements at Room Temperature 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.6.3 Circuits for Electrical Measurements 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8 Environmental and Endurance Tests 18 4.8.1 Electrical Measurements on Completion of Environmental Tests 18 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 18 4.8.3 Conditions for Operating Life Tests 19 4.8.4 Electrical Circuits for Operating Life Tests 19 4.8.5 Total Dose Irradiation Testing 19 4.8.6 Electrical Measurements 19 4.8.7 Electrical Circuits for Operating Life Tests 19 4.8.8 Electrical Circuits for Operating Life Tests 19 4.8.9 Total Dose Irradiation Testing 19 4.9.1 Application 19 4.9.2 Bias Conditions 19 4.9.2 Electrical Measurements 19 4.9.3 Electrical Measurements 19 4.9.4 Electrical Measurements 19 4.9.5 Electrical Measurements 19 4.9.6 Electrical Measurements 19 4.9.7 Electrical Measurements 19 4.9.8 Electrical Measurements 19 4.9.9 Electrical Measurements 19 4.9.1 Electrical Measurements 19 4.9.2 Electrical Measurements 19 4.9.3 Electrical Measurements 19 4.9.3 Electrical Measurements 19 4.9.4 Electrical Measurements 19 4.9.5 Electrical Measurements 19 4.9.6 Electrical Measurements 19 4.9.7 Electrical Measurements 19 4.9.8 Electrical Measurements 19 4.9.9 Electrical Measurements 19 4.9.0 Electrical Measurements 19 4.9.1 Electrical Measurements 19 4.9.2 Electrical Measurements 19 4.9.3 Electrical Measurements 19 4.9.4 Electrical Measurements 19 4.9.5 Electrical Measurements 19 4.9.6 Electrical Measurements 19 4.9.7 Electrical Measurements 19 4.9.8 Electrical Measurements 19 4.9.9 Electrical Measurements 19 4.9 Electrical Measurements 19 4.9 Electrical Measurements 19 4.0 Electrica			
4.5.3The SCC Component Number174.5.4Traceability Information184.6Electrical Measurements184.6.1Electrical Measurements at Room Temperature184.6.2Electrical Measurements at High and Low Temperatures184.6.3Circuits for Electrical Measurements184.7Burn-in Tests184.7.1Parameter Drift Values184.7.2Conditions for High Temperature Reverse Bias Burn-in184.7.3Electrical Circuit for High Temperature Reverse Bias Burn-in184.8Environmental and Endurance Tests234.8.1Electrical Measurements on Completion of Environmental Tests234.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23			
4.5.4Traceability Information184.6Electrical Measurements184.6.1Electrical Measurements at Room Temperature184.6.2Electrical Measurements at High and Low Temperatures184.6.3Circuits for Electrical Measurements184.7Burn-in Tests184.7.1Parameter Drift Values184.7.2Conditions for High Temperature Reverse Bias Burn-in184.7.3Electrical Circuit for High Temperature Reverse Bias Burn-in184.8Environmental and Endurance Tests234.8.1Electrical Measurements on Completion of Environmental Tests234.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23			
4.6. Electrical Measurements at Room Temperature 18 4.6.1 Electrical Measurements at High and Low Temperatures 18 4.6.2 Electrical Measurements at High and Low Temperatures 18 4.6.3 Circuits for Electrical Measurements 18 4.7 Burn-in Tests 18 4.7.1 Parameter Drift Values 18 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 18 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 18 4.8 Environmental and Endurance Tests 23 4.8.1 Electrical Measurements on Completion of Environmental Tests 23 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 23 4.8.3 Conditions for Operating Life Tests 23 4.8.4 Electrical Circuits for Operating Life Tests 23 4.8.5 Total Dose Irradiation Testing 23 4.9.1 Application 23 4.9.2 Bias Conditions 23 4.9.3 Electrical Measurements 23			
4.6.1 Electrical Measurements at Room Temperature 4.6.2 Electrical Measurements at High and Low Temperatures 4.6.3 Circuits for Electrical Measurements 4.7 Burn-in Tests 4.7.1 Parameter Drift Values 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 4.8 Environmental and Endurance Tests 4.8.1 Electrical Measurements on Completion of Environmental Tests 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 4.8.3 Conditions for Operating Life Tests 4.8.4 Electrical Circuits for Operating Life Tests 4.9 Total Dose Irradiation Testing 4.9.1 Application 4.9.2 Bias Conditions 4.9.3 Electrical Measurements 4.9.3 Electrical Measurements			
4.6.2Electrical Measurements at High and Low Temperatures184.6.3Circuits for Electrical Measurements184.7Burn-in Tests184.7.1Parameter Drift Values184.7.2Conditions for High Temperature Reverse Bias Burn-in184.7.3Electrical Circuit for High Temperature Reverse Bias Burn-in184.8Environmental and Endurance Tests234.8.1Electrical Measurements on Completion of Environmental Tests234.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23			
4.6.3 Circuits for Electrical Measurements 4.7 Burn-in Tests 4.7.1 Parameter Drift Values 4.7.2 Conditions for High Temperature Reverse Bias Burn-in 4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 4.8 Environmental and Endurance Tests 4.8.1 Electrical Measurements on Completion of Environmental Tests 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 4.8.3 Conditions for Operating Life Tests 4.8.4 Electrical Circuits for Operating Life Tests 4.9 Total Dose Irradiation Testing 4.9.1 Application 4.9.2 Bias Conditions 4.9.3 Electrical Measurements 23 4.9.3 Electrical Measurements			
4.7Burn-in Tests184.7.1Parameter Drift Values184.7.2Conditions for High Temperature Reverse Bias Burn-in184.7.3Electrical Circuit for High Temperature Reverse Bias Burn-in184.8Environmental and Endurance Tests234.8.1Electrical Measurements on Completion of Environmental Tests234.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23		· · · · · · · · · · · · · · · · · · ·	
4.7.1Parameter Drift Values184.7.2Conditions for High Temperature Reverse Bias Burn-in184.7.3Electrical Circuit for High Temperature Reverse Bias Burn-in184.8Environmental and Endurance Tests234.8.1Electrical Measurements on Completion of Environmental Tests234.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23			
4.7.2Conditions for High Temperature Reverse Bias Burn-in184.7.3Electrical Circuit for High Temperature Reverse Bias Burn-in184.8Environmental and Endurance Tests234.8.1Electrical Measurements on Completion of Environmental Tests234.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23			
4.7.3 Electrical Circuit for High Temperature Reverse Bias Burn-in 4.8 Environmental and Endurance Tests 4.8.1 Electrical Measurements on Completion of Environmental Tests 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 4.8.3 Conditions for Operating Life Tests 4.8.4 Electrical Circuits for Operating Life Tests 4.9 Total Dose Irradiation Testing 4.9.1 Application 4.9.2 Bias Conditions 4.9.3 Electrical Measurements 23			
4.8 Environmental and Endurance Tests 4.8.1 Electrical Measurements on Completion of Environmental Tests 4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests 4.8.3 Conditions for Operating Life Tests 4.8.4 Electrical Circuits for Operating Life Tests 4.9 Total Dose Irradiation Testing 4.9.1 Application 4.9.2 Bias Conditions 4.9.3 Electrical Measurements 23 4.9.3 Electrical Measurements		· · · · · · · · · · · · · · · · · · ·	
4.8.1Electrical Measurements on Completion of Environmental Tests234.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23		- The state of the	
4.8.2Electrical Measurements at Intermediate Points and on Completion of Endurance Tests234.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23			
4.8.3Conditions for Operating Life Tests234.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23		·	
4.8.4Electrical Circuits for Operating Life Tests234.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23		•	
4.9Total Dose Irradiation Testing234.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23		•	
4.9.1Application234.9.2Bias Conditions234.9.3Electrical Measurements23			
4.9.2Bias Conditions234.9.3Electrical Measurements23		· · · · · · · · · · · · · · · · · · ·	23
4.9.3 Electrical Measurements 23		• •	23
4.10 Special Testing 23		Electrical Measurements	23
	4.10	Special Testing	23



Rev. 'A'

PAGE 4

ISSUE 1

TABLE	<u>S</u>	<u>Page</u>
1(a)	Type Variants	6
1(b)	Maximum Ratings	8
2	Electrical Measurements at Room Temperature - D.C. Parameters	19
0	Electrical Measurements at Room Temperature - A.C. Parameters	19
3 4	Electrical Measurements at High and Low Temperatures Parameter Drift Values	20
4 5(a)		20
5(a) 5(b)	Conditions for High Temperature Reverse Bias Burn-in and Operating Life Tests Conditions for Power Burn-in	22
6	Electrical Measurements at Intermediate Points and on Completion of Endurance Testing	22
7	Electrical Measurements During and on Completion of Irradiation Testing	24 25
FIGURE		20
FIGURE	<u>:5</u>	
1	Parameter Derating Information	8
2	Physical Dimensions	9
3	Functional Diagram	14
4	Circuits for Electrical Measurements	21
5(a)	Electrical Circuit for High Temperature Reverse Bias Burn-in and Operating Life Tests	22
5(b)	Electrical Circuit for Power Burn-in	22
6	Bias Conditions for Irradiation Testing	24
APPEN	DICES (Applicable to specific Manufacturers only)	
'A'	Agreed Deviations for M/A-Com Ltd. (G.B.)	26



PAGE

ISSUE 1

5

1. **GENERAL**

1.1 SCOPE

This specification details the ratings, physical and electrical characteristics, test and inspection data for a Diode, Microwave, Silicon, Tuning Varactor, based on Types ML4351 thru ML4354. It shall be read in conjunction with ESA/SCC Generic Specification No. 5010, the requirements of which are supplemented herein.

1.2 <u>TYPE VARIANTS</u>

Variants of the basic diodes specified herein, which are also covered by this specification are given in Table 1(a).

1.3 MAXIMUM RATINGS

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the diodes specified herein, are as scheduled in Table 1(b).

1.4 PARAMETER DERATING INFORMATION

The derating information applicable to the diodes specified herein is shown in Figure 1.

1.5 PHYSICAL DIMENSIONS

The physical dimensions of the diodes specified herein are shown in Figure 2.

1.6 FUNCTIONAL DIAGRAM

The functional diagram, showing lead identification, of the diodes specified herein, is shown in Figure 3.

1.7 HANDLING PRECAUTIONS

These devices are susceptible to damage by electrostatic discharge. Therefore, suitable precautions shall be employed for protection during all phases of manufacture, testing, packaging, shipment and any handling.

These components are Categorised as Class 2 with a Minimum Critical Path Failure Voltage of 3400V.

2. APPLICABLE DOCUMENTS

The following documents form part of this specification and shall be read in conjunction with it:-

- (a) ESA/SCC Generic Specification No. 5010 for Discrete Microwave Semiconductor Components.
- (b) MIL-STD-750, Test Methods and Procedures for Semiconductor Devices.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply.



PAGE 6

ISSUE 1

TABLE 1(a) - TYPE VARIANTS

(1)	(2)	(3)		(4)	(5)	(6)
VARIANT	BASED ON TYPE	FIGURE	TOTAL CAPACITANCE C _T (pF)		QUALITY FACTOR (Q)	BODY-LID AND LEAD MATERIAL
						AND FINISH
			MIN	MAX ,	(MINIMUM)	1
01	ML4351 - 30	2(a)	0.56	0.84	1150	A7-D2
02	ML4351 - 31	2(b)	0.56	0.84	1150	A7-D2
03	ML4351 - 33	2(c)	0.61	0.89	1150	A7
04	ML4351 - 36	2(d)	0.56	0.84	1150	A7-D2
05	ML4351 - 96	2(e)	0.53	0.81	1150	A7-D2
06	ML4351 - 97	2(f)	0.53	0.81	1150	A7-D2
07	ML4351 - 103	2(g)	0.66	0.94	1150	A7-D2
08	ML4351 - 118	2(h)	0.60	0.88	1150	A7
09	ML4351 - 120	2(i)	0.51	0.79	1150	D2
10	ML4351 - 186	2(j)	0.51	0.79	1150	D2
11	ML4351 - 276	2(k)	0.51	0.79	1150	D2
12	ML4352 - 30	2(a)	0.74	1.06	1100	A7-D2
13	ML4352 - 31	2(b)	0.74	1.06	1100	A7-D2
14	ML4352 - 33	2(c)	0.79	1.11	1100	A7
15	ML4352 - 36	2(d)	0.74	1.06	1100	A7-D2
16	ML4352 - 96	2(e)	0.71	1.03	1100	A7-D2
17	ML4352 - 97	2(f)	0.71	1.03	1100	A7-D2
18	ML4352 - 103	2(g)	0.84	1.16	1100	A7-D2
19	ML4352 - 118	2(h)	0.78	1.10	1100	A7
20	ML4352 - 120	2(i)	0.69	1.01	1100	D2
21	ML4352 - 186	2(j)	0.69	1.01	1100	D2
22	ML4352 - 276	2(k)	0.69	1.01	1100	D2
23	ML4353 - 30	2(a)	1.00	1.40	1000	A7-D2
24	ML4353 - 31	2(b)	1.00	1.40	1000	A7-D2
25	ML4353 - 33	2(c)	1.05	1.45	1000	A7
26	ML4353 - 36	2(d)	1.00	1.40	1000	A7-D2
27	ML4353 - 96	2(e)	0.97	1.37	1000	A7-D2
28	ML4353 - 97	2(f)	0.97	1.37	1000	A7-D2
29	ML4353 - 103	2(g)	1.10	1.50	1000	A7-D2
30	ML4353 - 118	2(h)	1.04	1.44	1000	A7
31	ML4353 - 120	2(i)	0.95	1.35	1000	D2
32	ML4353 - 186	2(j)	0.95	1.35	1000	D2
33	ML4353 - 276	2(k)	0.95	1.35	1000	D2
34	ML4354 - 30	2(a)	1.55	2.05	900	A7-D2
35	ML4354 - 31	2(b)	1.55	2.05	900	A7-D2
36	ML4354 - 33	2(c)	1.60	2.10	900	A7



PAGE 7

ISSUE 1

TABLE 1(a) - TYPE VARIANTS (CONT'D)

VARIANT (1)	(2) BASED ON TYPE	(3) FIGURE	TOTAL CAPACITANCE C _T (pF)		(5) QUALITY FACTOR (Q) (MINIMUM)	(6) BODY-LID AND LEAD MATERIAL AND FINISH
			MIN	MAX	(IVIII VIII VIIOIVI)	ANDTINISH
37	ML4354 - 36	2(d)	1.55	2.05	900	A7-D2
38	ML4354 - 96	2(e)	1.53	2.02	900	A7-D2
39	ML4354 - 97	2(f)	1.52	2.02	900	A7-D2
40	ML4354 - 103	2(g)	1.65	2.15	900	A7-D2
41	ML4354 - 118	2(h)	1.59	2.09	900	A7
42	ML4354 - 120	2(i)	1.50	2.00	900	D2
43	ML4354 - 186	2(j)	1.50	2.00	900	D2
44	ML4354 - 276	2(k)	1.50	2.00	900	D2



PAGE 8

ISSUE -

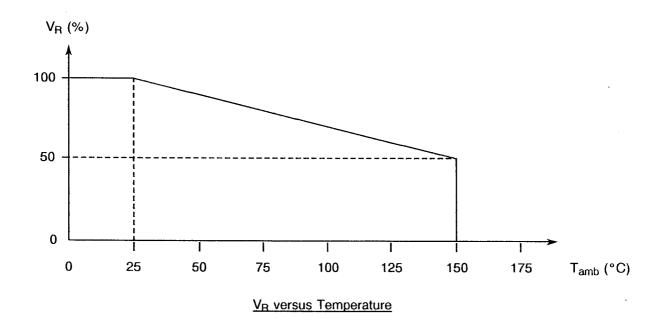
TABLE 1(b) - MAXIMUM RATINGS

No.	CHARACTERISTIC	SYMBOL	MAXIMUM RATINGS	UNIT	REMARKS
1	D.C. Reverse Voltage	V _R	- 60	٧	Note 1
2	Operating Temperature Range	T _{op}	-65 to +150	°C	T _{amb}
3	Storage Temperature Range	T _{stg}	-65 to +150	°C	
4	Soldering Temperature	T _{sol}	+230	°C	Note 2

NOTES

- 1. Measured at $I_R = 10\mu A$ and $T_{amb} = +25$ °C. For derating at $T_{amb} > +25$ °C, see Figure 1.
- 2. Duration 5 seconds maximum (at a distance of not less than 1.5mm from the body for Variants 10, 11, 21, 22, 32, 33, 43 and 44) and the same termination shall not be resoldered until 3 minutes have elapsed.

FIGURE 1 - PARAMETER DERATING INFORMATION



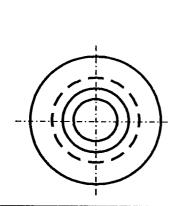


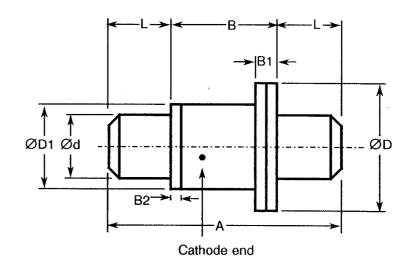
PAGE 9

ISSUE 1

FIGURE 2 - PHYSICAL DIMENSIONS

FIGURE 2(a) - VARIANTS 01, 12, 23, 34





SYMBOL	MILLIMETRES			
STWIBOL	MIN	MAX		
Α	5.20	5.72		
В	2.16	2.46		
B1	0.41	0.61		
B2	0.15	0.25		
Ød	1.52	1.63		
ØD	3.00	3.23		
ØD1	1.95	2.11		
L	1.52	1.63		

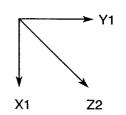
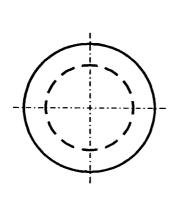
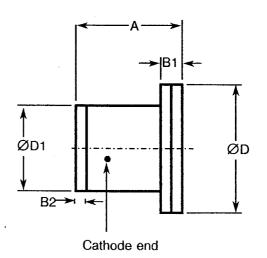
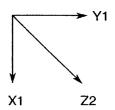


FIGURE 2(b) - VARIANTS 02, 13, 24, 35



SYMBOL	MILLIMETRES			
STWIDOL	MIN	MAX		
Α	2.16	2.46		
B1	0.41	0.61		
B2	0.15	0.25		
ØD	3.00	3.23		
ØD1	1.95	2.11		





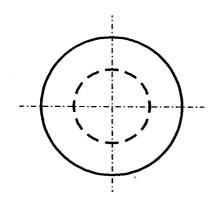


PAGE 10

ISSUE 1

FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

FIGURE 2(c) - VARIANTS 03, 14, 25, 36



	A ————————————————————————————————————					
Ød		;	•			- ØD
	←		-	► B		

SYMBOL	MILLIMETRES			
STWIDOL	MIN	MAX		
Α	1.41	1.85		
В	0.69	1.02		
B1	0.30	0.50		
B2	0.05	0.13		
Ød	0.61	0.66		
ØD	1.22	1.32		
L	0.74	0.79		

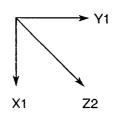
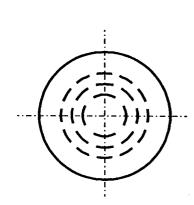
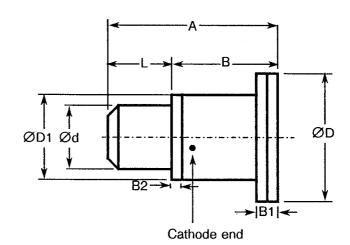
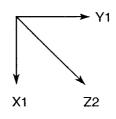


FIGURE 2(d) - VARIANTS 04, 15, 26, 37



SYMBOL	MILLIMETRES	
3 TWIDOL	MIN	MAX
. A	3.60	4.18
В	2.16	2.46
B1	0.41	0.61
B2	0.15	0.25
Ød	1.52	1.63
ØD	3.00	3.23
ØD1	1.95	2.11
L	1.52	1.63





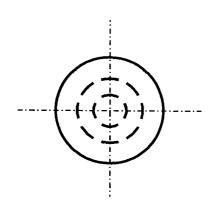


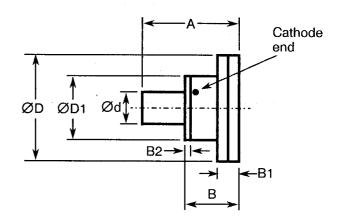
PAGE 11

ISSUE 1

FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

FIGURE 2(e) - VARIANTS 05, 16, 27, 38





SYMBOL	MILLIMETRES	
	MIN	MAX
Α	1.78	2.03
. В	1.02	1.27
B1	-	0.38
B2	0.10	0.25
Ød	0.61	0.66
ØD	1.98	2.18
ØD1	1.19	1.35

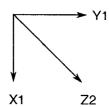
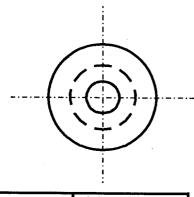
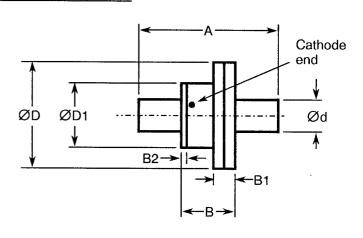
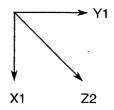


FIGURE 2(f) - VARIANTS 06, 17, 28, 39



SYMBOL	MILLIMETRES	
OTMBOL	MIN	MAX
Α	2.54	2.79
В	1.02	1.27
B1	-	0.38
B2	0.10	0.25
Ød	0.61	0.66
ØD	1.98	2.18
ØD1	1.19	1.35





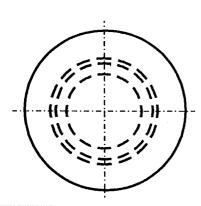


PAGE 12

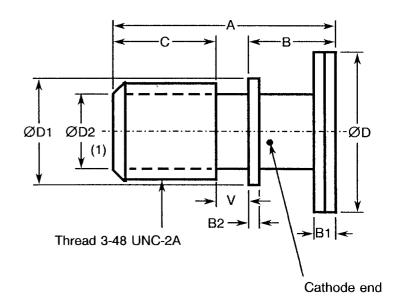
ISSUE 1

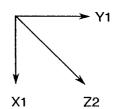
FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

FIGURE 2(g) - VARIANTS 07, 18, 29, 40



SYMBOL	MILLIMETRES	
STIVIDOL	MIN	MAX
Α	4.71	5.30
В	1.47	1.80
B1	0.41	0.61
B2	0.20	0.30
С	1.97	3.19
ØD	3.00	3.23
ØD1	2.49	2.59
ØD2	1.60	2.00
V	0.64	0.94

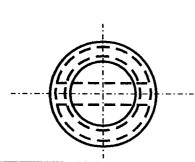




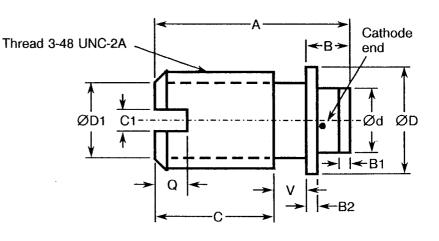
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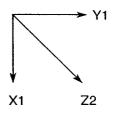
1. 6 spline socket, 1.39mm deep.

FIGURE 2(h) - VARIANTS 08, 19, 30, 41



SYMBOL	MILLIMETRES	
STMDOL	MIN	MAX
Α	4.19	4.70
В	0.77	1.04
B1	0.20	0.30
B2	0.22	0.28
С	2.21	3.29
C1	0.38	0.64
Ød	1.22	1.32
ØD	2.49	2.59
ØD1	1.60	2.00
Q	0.64	1.14
V	0.64	0.94





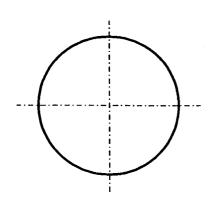


PAGE 13

ISSUE 1

FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

FIGURE 2(i) - VARIANTS 09, 20, 31, 42



	≺ ——A—	
Cathode end	*	ØD
B2 →		→ B1 <

SYMBOL	MILLIMETRES	
	MIN	MAX
Α	1.02	1.27
B1	0.23	0.33
B2	0.10	0.15
ØD	1.29	1.40

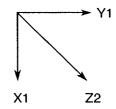
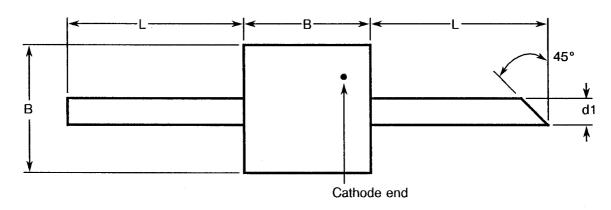
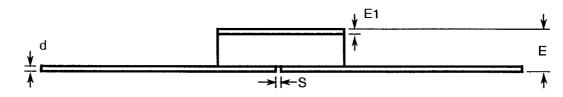
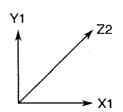


FIGURE 2(j) - VARIANTS 10, 21, 32, 43





SYMBOL	MILLIMETRES	
STWIDGE	MIN	MAX
В	2.39	2.62
d	0.07	0.15
d1	0.48	0.56
E	∙0.79	1.12
E1	0.10	0.18
L	3.30	5.84
S	0.10	-



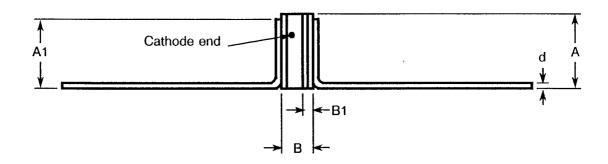


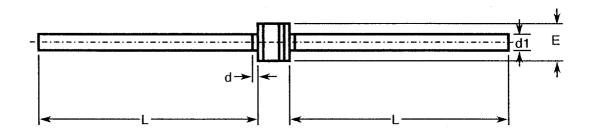
PAGE 14

ISSUE 1

FIGURE 2 - PHYSICAL DIMENSIONS (CONTINUED)

FIGURE 2(k) - VARIANTS 11, 22, 33, 44





SYMBOL	MILLIMETRES	
STIVIDOL	MIN	MAX
Α	1.35	2.54
A1	-	2.46
В	1.02	1.27
B1	-	0.38
d	0.07	0.15
d1	0.38	0.64
E	1.29	1.40
L	6.10	12.40

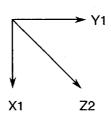


FIGURE 3 - FUNCTIONAL DIAGRAM



- 1. Anode
- 2. Cathode

NOTES

1. The cathode end shall be marked with a black dot or band. The marking will not be on the cathode connection but adjacent to it.



Rev. 'A'

PAGE 15

ISSUE 1

4. **REQUIREMENTS**

4.1 GENERAL

The complete requirements for procurement of the diodes specified herein shall be as stated in this specification and ESA/SCC Generic Specification No. 5010 for Discrete Microwave Semiconductor Components. Deviations from the Generic Specification applicable to this specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

4.2 <u>DEVIATIONS FROM GENERIC SPECIFICATION</u>

4.2.1 <u>Deviations from Special In-process Controls</u>

- (a) Para. 5.2.3, Total Dose Irradiation Testing: Shall be performed during qualification and extension of qualification.
- (b) Para. 5.2.3, Total Dose Irradiation Testing: Shall be performed during procurement on a lot acceptance basis at the total dose irradiation level specified in the purchase order.
- (c) Quality Factor Measurement (Q): 3 randomly chosen samples shall be encapsulated in the type of package shown in Figure 2(a) of this specification. After encapsulation, Quality Factor measurements shall be performed using the method shown in Figure 4 of this specification with $V_R = -4.0V$. The limits specified in Table 1(a) of this specification shall be met.

4.2.2 <u>Deviations from Final Production Tests</u> (Chart II)

None.

4.2.3 <u>Deviations from Burn-in and Electrical Measurements (Chart III)</u>

(a) Para. 9.21, High Temperature Reverse Bias Burn-in: Shall be performed at 50% of rated V_R.

4.2.4 <u>Deviations from Qualification Tests</u> (Chart IV)

(a) Para. 9.23, Special Testing: Shall not be performed.

4.2.5 <u>Deviations from Lot Acceptance Tests (Chart V)</u>

(a) Para. 9.23, Special Testing: Shall not be performed.

4.3 MECHANICAL AND ENVIRONMENTAL REQUIREMENTS

4.3.1 <u>Dimension Check</u>

The dimensions of the diodes specified herein shall be checked. They shall conform to those shown in Figure 2.



PAGE 16

ISSUE 1

4.3.2 Weight

The maximum weight of the diodes specified herein shall be:

Variant No.	Weight (g)
01, 12, 23, 34	0.12
02, 13, 24, 35	0.06
03, 14, 25, 36	0.01
04, 15, 26, 37	0.10
05, 16, 27, 38	0.015

Variant No.	Weight (g)
06, 17, 28, 39	0.022
07, 08, 18, 19, 29, 30, 40, 41	0.14
09, 20, 31, 42	0.014
10, 21, 32, 43	0.06
11, 22, 33, 44	0.025

4.3.3 <u>Terminal Strength</u>

The requirements for terminal strength testing are specified in Section 9 of ESA/SCC Generic Specification No. 5010. The test conditions shall be as follows:-

(a) Condition: 'A' (Tension)

Variants 10, 21, 32 and 43:

- Force: 5.1N.

- Duration: 5 seconds.

Variants 11, 22, 33 and 44:

Force: 1.22N.

- Duration: 5 seconds.

(b) Condition: 'D2' (Stud Torque)

Variants 07, 18, 29 and 40:

- Torque: 56mNm.

- Duration: 5 seconds.

Variants 08, 19, 30 and 41:

Torque: 42mNm.

Duration: 5 seconds.

(c) Condition: Compression

Variants 01, 02, 04, 07, 12, 13, 15, 18, 23, 24, 26, 29, 34, 35, 37 and 40:

Force: 50N.

- Duration: 5 seconds.

Variants 03, 05, 06, 08, 09, 14, 16, 17, 19, 20, 25, 27, 28, 30, 31, 36, 38, 39, 41 and 42:

Force: 10N.

- Duration: 5 seconds.

The compression test shall be performed by applying the specified force to the end-cap by means of a suitable weight applied for the specified time. On completion of the test, a visual examination shall be performed to check for damage to the end-cap or the ceramic body.



PAGE 17

ISSUE

4.4 MATERIALS AND FINISHES

The materials and finishes shall be as specified herein. Where a definite material is not specified, a material which will enable the diodes specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material shall not guarantee acceptance of the finished product.

4.4.1 Case

The case shall be hermetically sealed and have a ceramic body. The lid shall be brazed, welded or preform soldered.

4.4.2 Lead Materials and Finish

- (a) For Variants 01, 02, 04, 05, 06, 07, 12, 13, 15, 16, 17, 18, 23, 24, 26, 27, 28, 29, 34, 35, 37, 38, 39 and 40, the body material shall be Type 'A' with Type '7' finish and the lid material shall be Type 'D' with Type '2' finish, in accordance with the requirements of ESA/SCC Basic Specification No. 23500.
- (b) For Variants 03, 08, 14, 19, 25, 30, 36 and 41, the lead material shall be Type 'A' with Type '7' finish in accordance with the requirements of ESA/SCC Basic Specification No. 23500.
- (c) For Variants 09, 10, 11, 20, 21, 22, 31, 32, 33, 42, 43 and 44, the lead material shall be Type 'D' with Type '2' finish in accordance with the requirements of ESA/SCC Basic Specification No. 23500.

4.5 MARKING

4.5.1 General

The marking of components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700 and the following paragraphs. When the component is too small to accommodate all of the marking specified, as much as space permits shall be marked and the marking information, in full, shall accompany the component in its primary package.

The information to be marked and the order of precedence, shall be as follows:-

- (a) Cathode Identification.
- (b) The SCC Component Number.
- (c) Traceability Information.

4.5.2 Cathode Identification

Cathode identification shall be as shown in Figures 2 and 3 of this specification.

4.5.3 The SCC Component Number

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:

EE1000C01DE

	33120000101
Detail Specification Number	
Type Variant (see Table 1(a))	
Testing Level (B or C, as applicable)	
Total Dose Irradiation Level (if applicable)	

The Total Dose Irradiation Level designation shall be added for those devices for which a sample has been successfully tested to the level in question. For these devices, a code letter shall be added in accordance with the requirements of ESA/SCC Basic Specification No. 22900.



Rev. 'A'

PAGE 18

ISSUE 1

4.5.4 <u>Traceability Information</u>

Each component shall be marked in respect of traceability information as defined in ESA/SCC Basic Specification No. 21700.

4.6 <u>ELECTRICAL MEASUREMENTS</u>

4.6.1 <u>Electrical Measurements at Room Temperature</u>

The parameters to be measured at room temperature are scheduled in Table 2. Unless otherwise specified, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.6.2 <u>Electrical Measurements at High and Low Temperatures</u>

The parameters to be measured at high and low temperatures are scheduled in Table 3. Unless otherwise specified, the measurements shall be performed at $T_{amb} = +150(+0-3)$ °C.

4.6.3 <u>Circuits for Electrical Measurements</u>

A circuit for use in performing the quality factor measurement is shown in Figure 4.

4.7 BURN-IN TESTS

Burn-in shall be Category 1 of Chart III(a).

4.7.1 Parameter Drift Values

The parameter drift values applicable to burn-in are specified in Table 4 of this specification. Unless otherwise stated, the measurements shall be performed at T_{amb} = +22±3 °C. The parameter drift values (Δ) applicable to the scheduled parameters shall not be exceeded. In addition to these drift value requirements for a given parameter, the appropriate limit value specified in Table 2 shall not be exceeded.

4.7.2 <u>Conditions for High Temperature Reverse Bias Burn-in</u>

The requirements for the high temperature reverse bias burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 5010. The conditions for high temperature reverse bias burn-in shall be as specified in Table 5(a) of this specification.

4.7.3 Conditions for Power Burn-in

The requirements for power burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 5010. The conditions for power burn-in shall be as specified in Table 5(b) of this specification.

4.7.4 <u>Electrical Circuits for High Temperature Reverse Bias and Power Burn-in</u>

Circuits for use in performing the H.T.R.B and power burn-in tests are shown in Figures 5(a) and 5(b) of this specification.



PAGE 19 ISSUE 1

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - D.C. PARAMETERS

No.	CHARACTERISTICS	HARACTERISTICS SYMBOL MIL-STD-750 TEST CONDITIONS	LIMITS		UNIT		
	3, w u u 13 / 21 113 / 133		TEST METHOD	7207 CONSTITIONS	MIN.	MAX.	CIVIT
1	Reverse Current 1	I _{R1}	4016	V _R = -60V	-	10	μΑ
2	Reverse Current 2	I _{R2}	4016	V _R = -30V	-	50	nA
3	Forward Voltage	V _F	4011	I _F = 100mA	-	1.0	V

TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - A.C. PARAMETERS

No.	CHARACTERISTICS	SYMBOL	SYMBOL MIL-STD-750 TI	MIL-STD-750 TEST TEST METHOD CONDITIONS	LIM	ITS	UNIT
	OTATAOTENISTICS	STIVIBUL	TEST METHOD		MIN.	MAX.	
4	Total Capacitance	C _T	4001	V _R = -4.0V f = 1.0MHz	Not	e 1	pF
5	Total Capacitance Ratio	-	4001	$V_R = 0V$ $V_R = -60V$ $f = 1.0MHz$ Note 2 Variants 01 to 11 Variants 12 to 22 Variants 23 to 33 Variants 34 to 44	3.5 4.2 4.5 5.5	- - - -	

NOTES

1. See Column 4 of Table 1(a).

2. Ratio =
$$\frac{C_T \text{ at } V_R = 0V}{C_T \text{ at } V_R = -60V}$$



PAGE 20 ISSUE 1

TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES

No.	CHARACTERISTICS	SYMBOL	SPEC.AND/OR	TEST	LIM	IITS	UNIT
140.	0.1.1.1.10.1.2.1.10.1.100	OTWIDOL	TEST METHOD	CONDITIONS	MIN.	MAX.	DIVIT
2	Reverse Current 2	I _{R2}	As per Table 2	As per Table 2	_	10	μΑ

TABLE 4 - PARAMETER DRIFT VALUES

No.	CHARACTERISTICS	SYMBOL	SPEC.AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS (Δ)	UNIT
2	Reverse Current 2	I _{R2}	As per Table 2	As per Table 2	± 10 (1) or (2) ± 100 (1)	nA %
3	Forward Voltage	V _F	As per Table 2	As per Table 2	± 100 (1)	mV

NOTES

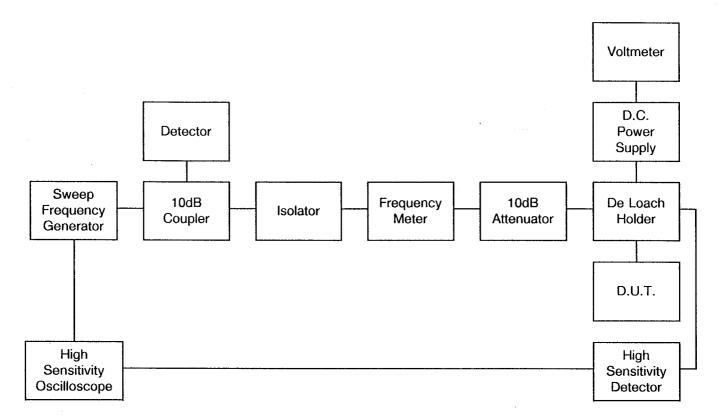
- 1. $\Delta 1 = \Delta 2$.
- 2. Whichever is the greater, referred to the initial measurement.



PAGE 21

ISSUE 1

FIGURE 4 - CIRCUITS FOR ELECTRICAL MEASUREMENTS





Rev. 'A'

PAGE 22

ISSUE 1

TABLE 5(a) - CONDITIONS FOR HIGH TEMPERATURE REVERSE BIAS BURN-IN AND OPERATING LIFE TESTS

No.	CHARACTERISTICS	SYMBOL	CONDITIONS	UNIT
1	Ambient Temperature	T _{amb}	+ 150(+ 0 - 3)	°C
2	Reverse Voltage	V _R	-30	٧

TABLE 5(b) - CONDITIONS FOR POWER BURN-IN

No.	CHARACTERISTICS	SYMBOL	CONDITIONS	UNIT
1	Ambient Temperature	T _{amb}	+ 125(+ 0 - 3)	°C
2	Forward Current	l _F	25	mA

FIGURE 5(a) - ELECTRICAL CIRCUIT FOR HIGH TEMPERATURE REVERSE BIAS BURN-IN AND OPERATING LIFE TESTS

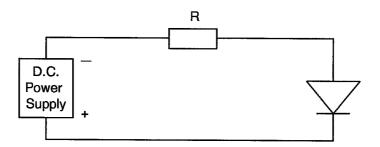
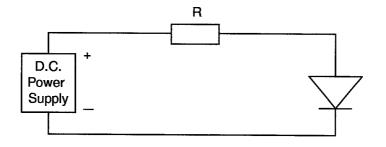


FIGURE 5(b) - ELECTRICAL CIRCUIT FOR POWER BURN-IN





Rev. 'A'

PAGE 23

ISSUE 1

4.8 <u>ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC SPECIFICATION NO. 5010)</u>

4.8.1 <u>Electrical Measurements on Completion of Environmental Tests</u>

The parameters to be measured on completion of environmental tests are scheduled in Table 2. Unless otherwise stated, the measurements shall be performed at T_{amb} = +22 ±3 °C.

4.8.2 <u>Electrical Measurements at Intermediate Points and on Completion of Endurance Tests</u>

The parameters to be measured at intermediate points and on completion of endurance tests are scheduled in Table 6. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.3 <u>Conditions for Operating Life Tests (Part of Endurance Testing)</u>

The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 5010. The conditions for operating life testing are specified in Table 5(a) of this specification.

4.8.4 <u>Electrical Circuits for Operating Life Tests</u>

The circuit to be used for performance of the operating life test shall be the same as shown in Figure 5(a) for High Temperature Reverse Bias Burn-in.

4.9 TOTAL DOSE IRRADIATION TESTING

4.9.1 Application

If specified in Para. 4.2.1 of this specification, total dose irradiation testing shall be performed in accordance with the requirements of ESA/SCC Basic Specification No. 22900.

4.9.2 Bias Conditions

Continuous bias shall be applied during irradiation testing as shown in Figure 6 of this specification.

4.9.3 <u>Electrical Measurements</u>

The parameters to be measured prior to irradiation exposure are scheduled in Table 2 of this specification. Only devices which meet the requirements of Table 2 shall be included in the test sample.

The parameters to be measured during and on completion of irradiation testing are scheduled in Table 7 of this specification.

4.10 SPECIAL TESTING

Not applicable.



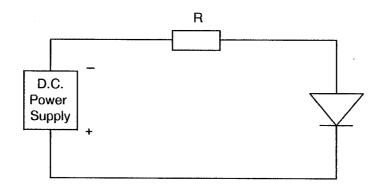
PAGE 24

ISSUE 1

TABLE 6 - ELECTRICAL MEASUREMENTS AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR	TEST	LIMITS	LINUT
	OTATAOTETISTICS	STIVIDOL	TEST METHOD	CONDITIONS	MIN. MA	X. UNIT
1	Reverse Current 1	I _{R1}	As per Table 2	As per Table 2	As per Table	2 μΑ
2	Reverse Current 2	I _{R2}	As per Table 2	As per Table 2	As per Table	2 nA
3	Forward Voltage	V _F	As per Table 2	As per Table 2	As per Table	2 V
4	Total Capacitance	C _T	As per Table 2	As per Table 2	As per Table	2 pF

FIGURE 6 - BIAS CONDITIONS FOR IRRADIATION TESTING



NOTES

1. A reverse bias of $V_R = -30V$, shall be applied.



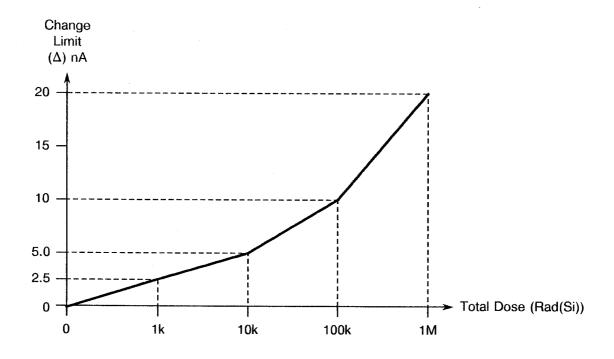
PAGE 25 ISSUE 1

TABLE 7 - ELECTRICAL MEASUREMENTS DURING AND ON COMPLETION OF IRRADIATION TESTING

No	. CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITIONS	CHANGE LIMITS (Δ)	UNIT
2	Reverse Current 2	I _{R2}	As per Table 2	As per Table 2	Note 1	nA

NOTES

1. The graph given below shall be used to determine the maximum permitted change.





PAGE 26

ISSUE 1

APPENDIX 'A'

Page 1 of 1

AGREED DEVIATIONS FOR M/A-Com LTD. (G.B.)

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Para. 4.2.2	Para. 9.4, "High Temperature Stabilisation Bake": May be performed at +150(+0-3) °C.